



SDI Review Form 1.6

Journal Name:	Physical Science International Journal
Manuscript Number:	2013_PSIJ_8754
Title of the Manuscript:	Microracks Detection Techniques in Silicon Solar Cell
Type of the Article	Review article

General guideline for Peer Review process:

This journal's peer review policy states that **NO** manuscript should be rejected only on the basis of '**lack of Novelty**', provided the manuscript is scientifically robust and technically sound.

To know the complete guideline for Peer Review process, reviewers are requested to visit this link:

(<http://www.sciencedomain.org/page.php?id=sdi-general-editorial-policy#Peer-Review-Guideline>)



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PART 1: Review Comments

	Reviewer's comment	Author's comment (if agreed with reviewer, correct the manuscript and highlight that part in the manuscript. It is mandatory that authors should write his/her feedback here)
Compulsory REVISION comments	<p>Line 27: Errata: or lesser Corrige: or less</p> <p>From the introduction it seems that the problem of crack detection in Silicon solar cell is relevant only during the production state, to discard micro-cracked cells. Actually, the introduction should be expanded by mentioned that the problem of crack detection is important also in the field, and it caused by vibration, installation and use of PV modules. An article discussing these issues related to durability is the following: [M. Paggi, M. Corrado, M.A. Rodriguez: "A multi-physics and multi-scale numerical approach to microcracking and power-loss in photovoltaic modules", Composite Structures, Vol. 95, 630-638, 2013].</p> <p>An additional reference important to be mentioned, which is related to the use of electroluminescence for cracks detection is: [M. Sander, S. Dietrich, M. Pander, M. Ebert, J. Bagdahn: "Systematic investigation of cracks in encapsulated solar cells after mechanical loading", Solar Energy Materials and Solar Cells, Vol. 111, 82-89, 2013].</p>	<p>Line 27: It is corrected now.</p> <p>I already mention that the mishandling of solar cell may also leads microcracks. See the line number 40-42</p> <p>I have added one reference suggested by the reviewer.</p> <p>Second reference is for stress testing which is a destructive technique and our motto here only to discuss about the non-destructive techniques. Because destructive techniques sometimes may lead cracks in the cells.</p>



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	In situ techniques for crack detection should be mentioned in a specific section. They include thermal imaging and UV lamps (XWOM). Please analyze the huge amount of published literature on this subject.	
<u>Minor</u> REVISION comments		
<u>Optional/General</u> comments		